

STL6NM60N

N-channel 600 V - 0.85 Ω - 5.75 A - PowerFLAT™ (5x5) ultra low gate charge MDmesh™ II Power MOSFET

Features

Туре	V _{DSS @} T _{JMAX}	R _{DS(on)} Max	Ι _D
STL6NM60N	650 V	< 0.92 Ω	5.75 A ⁽¹⁾

- 1. The value is rated according Rthj-case
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

Application

Switching applications

Description

This series of devices implements the second generation of MDmesh[™] Technology. This revolutionary Power MOSFET associates a new vertical structure to the Company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the nost demanding high efficiency converters.

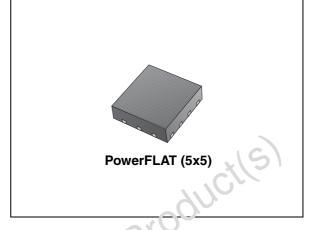
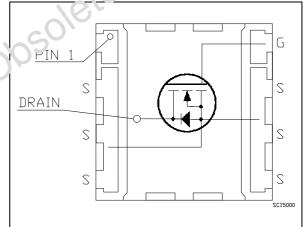


Figure 1. Internal schematic diagram



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Order code	Marking	Package	Packaging
STL6NM60N	L6NM60N	PowerFLAT™ (5x5)	Tape & reel

Contents

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Electrical ratings 1

Table 2. Al	bsolute maximu	m ratings
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Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage ($V_{GS} = 0$)	600	V
V _{GS}	Gate-source voltage	± 25	V
I _D ⁽¹⁾	Drain current (continuous) at $T_C = 25 \text{ °C}$ (steady state)	5.75	Α
I _D ⁽¹⁾	Drain current (continuous) at T _C =100 °C	3.62	Α
I _{DM} ^{(1),(2)}	Drain current (pulsed)	23	Α
I _D ⁽³⁾	Drain current (continuous) at T _C = 25 °C	1	Α
I _D ⁽³⁾	Drain current (continuous) at T _C =100 °C	0.65	Α
I _{DM} ^{(2), (3)}	Drain current (pulsed)	4	Α
P _{TOT} ⁽³⁾	Total dissipation at $T_C = 25 \ ^{\circ}C$ (steady state)	2.1	w
P _{TOT} ⁽¹⁾	Total dissipation at $T_C = 25 \ ^{\circ}C$ (steady state)	70	W
	Derating factor ⁽³⁾	0.02	W/°C
dv/dt (4)	Peak diode recovery voltage slope	5	V/ns
T _J T _{stg}	Operating junction temperature storage temperature	-55 to 150	°C
	is rated according Rthj-case		

2. Pulse width limited by safe operating area.

3. When mounted on FR-4 board of 1inch², 2oz Cu

4. $I_{SD} \leq 4.6A$, dv/dt $\leq 400A/\mu s$, $V_{DD} = 80\% V_{(BR)DSS}$

Table 3. Thermal resistance

Symbol	Parameter	Тур	Мах	Unit
R _{thj-case}	Thermal resistance junction-case		1.8	°C/W
R _{thj-pcb} ⁽¹⁾	Thermal resistance junction-pcb	31.2	58.5	°C/W

1. When mounted on FR-4 board of 1inch², 2oz Cu, t < 10 sec

Table 4. Avalanche characteristics

Symbol	Parameter	Тур	Unit
I _{AS}	Avalanche current, repetitive or not-repetitive ⁽¹⁾	2	А
E _{AS}	Single pulse avalanche energy ⁽²⁾	65	mJ

1. Pulse width limited by Tjmax

2. Starting Tj = 25 °C, $I_D = I_{AS}$, $V_{DD} = 50$ V



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Electrical characteristics 2

(T_{CASE}=25°C unless otherwise specified)

Table J.	On/on states						
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit	
V _{(BR)DSS}	Drain-source breakdown voltage	$I_D = 1 \text{ mA}, V_{GS} = 0$	600			V	
dv/dt ⁽¹⁾	Drain-source voltage slope	V _{DD} = 480 V, V _{GS} = 10 V, I _D = 4.6 A		40		V/ns	
I _{DSS}	Zero gate voltage drain current ($V_{GS} = 0$)	V _{DS} = Max rating, V _{DS} = Max rating @125 °C			1 100	μΑ μΑ	
I _{GSS}	Gate body leakage current (V _{DS} = 0)	V _{GS} = ±20 V			±100	nA	
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	2	3	4	v	
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10 V, I _D = 2.3 A		0.85	0.92	Ω	
1. Characteristics value at turn off on inductive load							
Table 6. Dynamic							

Table 5. **On/off states**

Dynamic					
Parameter	Test conditions	Min.	Тур.	Max.	Unit
Forward transconductance	$V_{DS} = 15 \text{ V}, I_{D} = 2.3 \text{ A}$		4		S
Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} =50V, f=1 MHz, V _{GS} =0		420 30 4		pF pF pF
Output equivalent capacitance	V_{GS} =0, V_{DS} =0 to 480 V		70		рF
Gate input resistance	f=1 MHz Gate DC Bias=0 test signal level = 20 mV open drain		6		Ω
Total gate charge Gate-source charge Gate-drain charge	V_{DD} = 480 V, I _D = 4.6 A V _{GS} =10 V (see Figure 15)		13 2 7		nC nC nC
	Parameter Forward transconductance Input capacitance Output capacitance Reverse transfer capacitance Output equivalent capacitance Gate input resistance Total gate charge Gate-source charge	ParameterTest conditionsForward transconductance $V_{DS} = 15 \text{ V}, I_D = 2.3 \text{ A}$ Input capacitanceOutput capacitanceOutput capacitance $V_{DS} = 50 \text{ V}, f=1 \text{ MHz}, V_{GS} = 0$ Output equivalent capacitance $V_{GS} = 0, V_{DS} = 0 \text{ to } 480 \text{ V}$ Output equivalent capacitance $f=1 \text{ MHz} \text{ Gate DC Bias} = 0$ test signal level = 20 mV open drainTotal gate charge Gate-source charge $V_{DD} = 480 \text{ V}, I_D = 4.6 \text{ A}$ $V_{GS} = 10 \text{ V}$	ParameterTest conditionsMin.Forward transconductance $V_{DS} = 15 \text{ V}, 1_D = 2.3 \text{ A}$ Input capacitanceInput capacitance $V_{DS} = 50 \text{ V}, f=1 \text{ MHz}, V_{GS}=0$ $V_{DS} = 50 \text{ V}, f=1 \text{ MHz}, V_{GS}=0$ Output capacitance $V_{GS} = 0, V_{DS} = 0 \text{ to } 480 \text{ V}$ $V_{GS} = 0, V_{DS} = 0 \text{ to } 480 \text{ V}$ Output equivalent capacitance $f=1 \text{ MHz} \text{ Gate DC Bias}=0$ test signal level = 20 mV open drain $V_{DD} = 480 \text{ V}, I_D = 4.6 \text{ A}$ $V_{GS} = 10 \text{ V}$	ParameterTest conditionsMin.Typ.Forward transconductance $V_{DS} = 15 \text{ V}, I_D = 2.3 \text{ A}$ 4Input capacitance $V_{DS} = 50 \text{ V}, f=1 \text{ MHz}, V_{GS}=0$ 420Output capacitance $V_{DS} = 50 \text{ V}, f=1 \text{ MHz}, V_{GS}=0$ 420Output equivalent capacitance $V_{GS} = 0, V_{DS} = 0 \text{ to } 480 \text{ V}$ 70Gate input resistancef=1 \text{ MHz Gate DC Bias=0} test signal level = 20 mV open drain6Total gate charge Gate-source charge $V_{DD} = 480 \text{ V}, I_D = 4.6 \text{ A}$ 13 2	ParameterTest conditionsMin.Typ.Max.Forward transconductance $V_{DS} = 15 \text{ V}, I_D = 2.3 \text{ A}$ 4Input capacitance $V_{DS} = 15 \text{ V}, I_D = 2.3 \text{ A}$ 4Input capacitance $V_{DS} = 50 \text{ V}, f=1 \text{ MHz}, V_{GS} = 0$ 420Output capacitance $V_{DS} = 50 \text{ V}, f=1 \text{ MHz}, V_{GS} = 0$ 4Output equivalent capacitance $V_{GS} = 0, V_{DS} = 0 \text{ to } 480 \text{ V}$ 70Gate input resistancef=1 \text{ MHz Gate DC Bias=0} test signal level = 20 mV open drain6Total gate charge Gate-source charge $V_{DD} = 480 \text{ V}, I_D = 4.6 \text{ A}$ $V_{GS} = 10 \text{ V}$ 13

1. Pulsed: pulse duration= 300 μ s, duty cycle 1.5%

2. $C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}



	•					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r t _{d(off)} t _f	Turn-on delay time Rise time Turn-off delay time Fall time	V_{DD} = 300 V, I_D = 2.3 A, R _G = 4.7 Ω , V _{GS} = 10 V (see Figure 14)		10 8 40 9		ns ns ns ns

Table 7. Switching times

Table 8. Source drain diode

Symbol	Parameter	Test conditions	Min	Тур.	Max	Unit
I _{SD}	Source-drain current				1	А
I _{SDM} ⁽¹⁾ , ⁽²⁾	Source-drain current (pulsed)				4	А
V _{SD} ⁽³⁾	Forward on voltage	I _{SD} = 4.6 A, V _{GS} =0			1.3	v
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} = 4.6 A, di/dt = 100 A/μs, V _{DD} =20 V <i>(see Figure 16)</i>	0	300 2 12		ns nC A
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} = 4.6 A, di/dt = 100 A/μs, V _{DD} =20 V, Tj= 150 °C <i>(see Figure 16)</i>		470 3 12		ns nC A
1. Pulse wic	Ith limited by safe operating area	105		•		

2. When mounted on FR-4 board of 1inch², 2oz Cu

, duty 3. Pulsed: pulse duration=300µs, duty cycle 1.5%

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2.1 Electrical characteristics (curves)

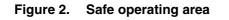
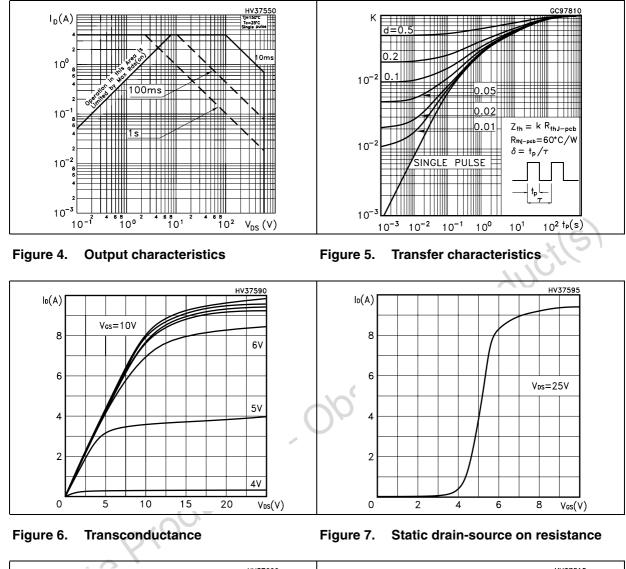
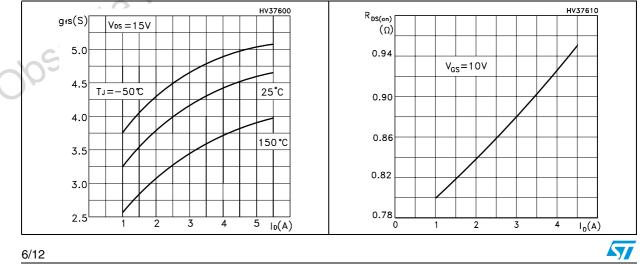


Figure 3. Thermal impedance





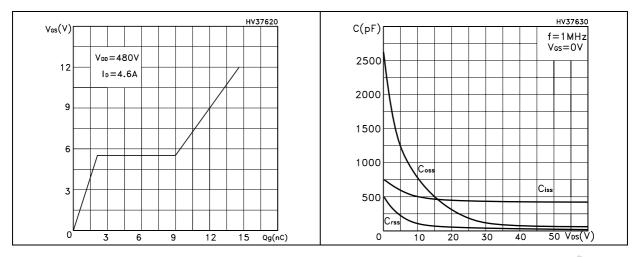


Figure 8. Gate charge vs gate-source voltage Figure 9. Capacitance variations

Figure 10. Normalized gate threshold voltage vs temperature

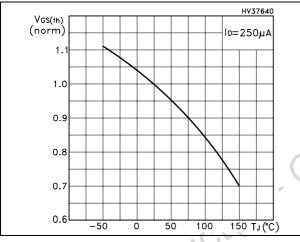


Figure 12. Source-drain diode forward characteristics

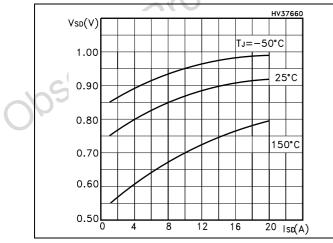


Figure 11. Normalized on resistance vs temperature

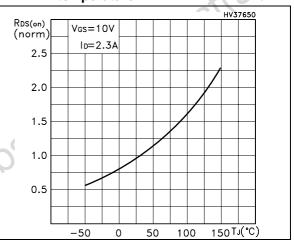
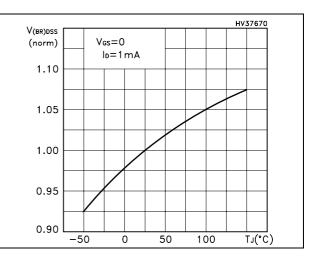


Figure 13. Normalized B_{VDSS} vs temperature



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3 Test circuit

Figure 14. Switching times test circuit for resistive load

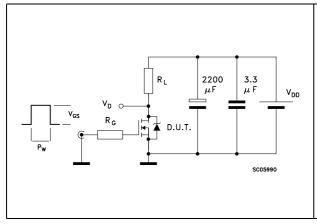
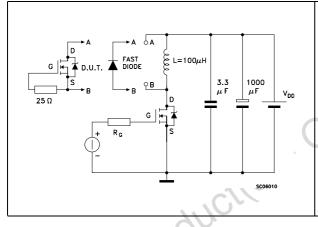
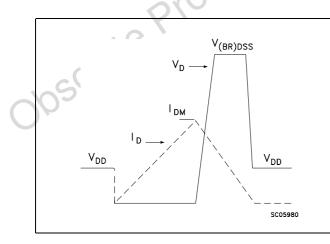
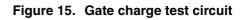


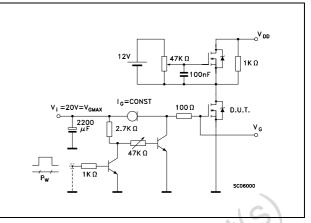
Figure 16. Test circuit for inductive load switching and diode recovery times

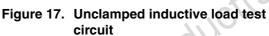












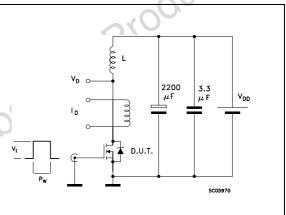
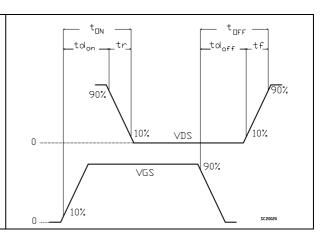


Figure 19. Switching time waveform



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4 Package mechanical data

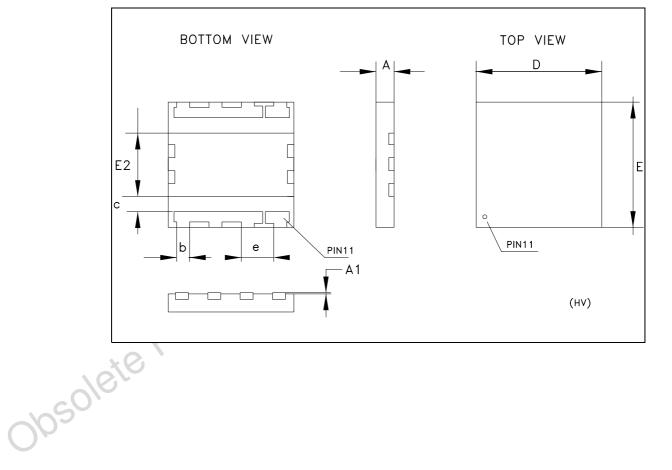
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obsolete Product(s). Obsolete Product(s)

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DIM.	mm.			inch		
	MIN.	ТҮР	MAX.	MIN.	TYP.	MAX.
А	0.80	0.90	1.00	0.031	0.035	0.039
A1		0.02	0.05		0.0007	0.002
A3		0.24			0.009	
b	0.43	0.51	0.58	0.016	0.020	0.022
с	0.64	0.71	0.79	0.025	0.027	0.031
D		5.00			0.19	
E		5.00			0.19	
E2	2.49	2.57	2.64	0.01	0.10	0.103
е		1.27			0.05	



PowerFLAT[™](5x5) MECHANICAL DATA

5 Revision history

Table 9. Document revision history

Date	Revision	Changes	
04-May-2007	1	First release	
23-May-2007	2	Update test conditions on Table 7	
27-Nov-2007	3	Mechanical data has been updated	

Obsolete Product(s) - Obsolete Product(s)



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